## **Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application.

## **Listing of Claims:**

Claim 1 (currently amended): A solder alloy consisting essentially of, by weight, at least 3.1% 3.0% to 3.5% silver, greater than 3% 1% to about 15% copper, the balance tin and incidental impurities, the alloy having an effective melting range of about 215°C to about 222°C above which the alloy does not exhibit a mushy zone.

Claim 2 (original): A solder alloy according to claim 1, wherein the solder alloy has a solidus temperature in a range of about 215°C to about 218°C.

Claim 3 (original): A solder alloy according to claim 1, wherein the solder alloy has a liquidus temperature of about 290°C or more.

Claim 4 (currently amended): A solder alloy according to claim 1, wherein the copper content is at least 4 about 2 to about 10 weight percent of the alloy.

Claim 5 (original): A solder alloy according to claim 1, wherein the copper content is greater than 4 weight percent of the alloy.

Claim 6 (original): A solder alloy according to claim 1, wherein the copper content is greater than 6 weight percent of the alloy.

Claim 7 (currently amended): A solder alloy according to claim 1, wherein the silver content is at least 3.2 greater than 3.0 and less than 3.5 weight percent of the alloy.

Claim 8 (currently amended): A solder alloy according to claim 1, wherein the silver content is at least 3.3 3.1 to 3.4 weight percent of the alloy.

Claim 9 (original): A solder alloy according to claim 1, wherein the solder alloy consists of, by weight, about 3.0% silver, about 15% copper, the balance tin and incidental impurities.

Claim 10 (original): A solder alloy according to claim 1, wherein the solder alloy consists of, by weight, about 3.1% silver, about 12% copper, the balance tin and incidental impurities.

Claim 11 (original): A solder alloy according to claim 1, wherein the solder alloy consists of, by weight, about 3.2% silver, about 8% to about 10% copper, the balance tin and incidental impurities.

Claim 12 (original): A solder alloy according to claim 1, wherein the solder alloy consists of, by weight, about 3.3% silver, about 4% to about 6% copper, the balance tin and incidental impurities.

Claim 13 (currently amended): A solder alloy according to claim 1, wherein the solder alloy contains consists of, by weight, about 3.4% silver, about 2% copper, the balance tin and incidental impurities.

Claim 14 (original): A solder alloy according to claim 1, wherein the solder alloy is in the form of a solder bump on a surface-mount integrated circuit device.

Claim 15 (original): A solder alloy according to claim 1, wherein the solder alloy is in the form of a solder joint attaching a component to a laminate or ceramic substrate.

Claim 16 (currently amended): A solder bump formed of an alloy consisting essentially of, by weight, 3.0% to 3.5% silver, greater than 3% about 2% to about 15% copper, the balance tin and incidental impurities, the alloy having a solidus temperature in a range of about 215°C to about 218°C, a liquidus temperature of at least 290°C, and an effective melting range of about 215°C to about 222°C above which the alloy does not exhibit a mushy zone.

Claim 17 (original): A solder bump according to claim 16, wherein the copper content is greater than 4 weight percent of the alloy.

Claim 18 (original): A solder bump according to claim 16, wherein the copper content is greater than 6 weight percent of the alloy.

Claim 19 (original): A solder bump according to claim 16, wherein the silver content is 3.1 to 3.4 weight percent of the alloy.

Claim 20 (currently amended): A solder bump according to claim 19, wherein the copper content is greater than 3% about 2 to about 10 weight percent of the alloy.

Claim 21 (original): A solder bump according to claim 16, wherein the alloy consists of, by weight, about 3.0% silver, about 15% copper, the balance tin and incidental impurities.

Claim 22 (original): A solder bump according to claim 16, wherein the alloy consists of, by weight, about 3.1% silver, about 12% copper, the balance tin and incidental impurities.

Claim 23 (original): A solder bump according to claim 16, wherein the alloy consists of, by weight, about 3.2% silver, about 8% to about 10% copper, the balance tin and incidental impurities.

Claim 24 (original): A solder bump according to claim 16, wherein the alloy consists of, by weight, about 3.3% silver, about 4% to 6% copper, the balance tin and incidental impurities.

Claim 25 (currently amended): A solder bump according to claim 16, wherein the alloy contains consists of, by weight, about 3.4% silver, about 2% copper, the balance tin and incidental impurities.

Claim 26 (currently amended): A solder bump according to claim 16, wherein the silver content of the alloy is 3.3 to 3.4 weight percent of the alloy, and the copper content of the alloy is 2.0 to 4.0 weight percent of the alloy.

Claim 27 (original): A solder bump according to claim 16, wherein the solder bump is on a surface-mount integrated circuit device.

Claim 28 (original): A solder bump according to claim 16, wherein the solder bump is in the form of a solder joint attaching a component to a laminate or ceramic substrate.

Claim 29 (currently amended): A solder reflow process performed with an alloy consisting essentially of, by weight, 3.0% to 3.5% silver, greater than 3% 1% to about 15% copper, the balance tin and incidental impurities, the process comprising the step of heating the alloy to a peak temperature of between about 240°C to about 260°C, at which the alloy reflows without exhibiting a mushy zone.

Claim 30 (original): A solder reflow process according to claim 29, wherein the solder alloy has a solidus temperature in a range of about 215°C to about 218°C.

Claim 31 (original): A solder reflow process according to claim 29, wherein the solder alloy has a liquidus temperature of about 290°C or more.

Claim 32 (currently amended): A solder reflow process according to claim 29, wherein the copper content is greater than 3% about 2 to about 10 weight percent of the alloy.

Claim 33 (original): A solder reflow process according to claim 29, wherein the copper content is greater than 4 weight percent of the alloy.

Claim 34 (original): A solder reflow process according to claim 29, wherein the copper content is greater than 6 weight percent of the alloy.

Claim 35 (original): A solder reflow process according to claim 29, wherein the silver content is greater than 3.0 and less than 3.5 weight percent of the alloy.

Claim 36 (original): A solder reflow process according to claim 29, wherein the silver content is 3.1 to 3.4 weight percent of the alloy.

Claim 37 (original): A solder reflow process according to claim 29, wherein

the solder alloy consists of, by weight, about 3.0% silver, about 15% copper, the balance tin and incidental impurities.

Claim 38 (original): A solder reflow process according to claim 29, wherein the solder alloy consists of, by weight, about 3.1% silver, about 12% copper, the balance tin and incidental impurities.

Claim 39 (original): A solder reflow process according to claim 29, wherein the solder alloy consists of, by weight, about 3.2% silver, about 8% to about 10% copper, the balance tin and incidental impurities.

Claim 40 (original): A solder reflow process according to claim 29, wherein the solder alloy consists of, by weight, about 3.3% silver, about 4% to about 6% copper, the balance tin and incidental impurities.

Claim 41 (currently amended): A solder reflow process according to claim 29, wherein the solder alloy contains consists of, by weight, about 3.4% silver, about 2% copper, the balance tin and incidental impurities.

Claim 42 (original): A solder reflow process according to claim 29, wherein

the process causes the solder alloy to form a solder bump on a surface-mount integrated circuit device.

Claim 43 (original): A solder reflow process according to claim 29, wherein the process causes the solder alloy to form a solder joint attaching a component to a laminate or ceramic substrate.